

RELIABILITY MONITOR

PRODUCT	MONITOR DATE	DATE CODE	ASSEMBLY FACILITY	ASSEMBLY LOT NO	PROCESS TYPE	PACKAGE TYPE
DS2502	Mar-96	9546 A6	CARSEM	DM534656ATA	1.2μ OX/NI EPROM	08 SOIC 150

STRESS/JOB NO.

**READPOINT
(Sample Size/No. of Fails)**

Preconditioning (P/C):
HTC Vapor Phase
P-17086

<u>Electrical</u>	<u>Cum %</u>
229/1	0.4%
F1	

Infant / High Voltage Life
125°C, 7.0 V.
P-17098, P-17138

<u>48 Hr</u>	<u>336 Hr</u>	<u>1KHr</u>	<u>*Failure Rate</u>
226/1	70/0	70/0	72 Fits
F2			

*Chi Squared Method, 60% C. L., 55°C & 5.5V; Temperature Derating: Ea = 0.7 ev; Voltage Derating B = 1.0

Temp Cycle
-55°C to +125°C
P-17139

<u>300 ~</u>	<u>1K ~</u>	<u>Cum %</u>
38/0	38/0	0.0%

Biased Moisture
85°C/85% RH, 5.5 V.
P-17140

<u>274 Hr</u>	<u>959 Hr</u>	<u>Cum %</u>
73/0	73/0	0.0%

Storage Life
150°C, No bias
P-17141

<u>336 Hr</u>	<u>1KHr</u>	<u>Cum %</u>
37/0	37/0	0.0%

Failure Mode

F1: Preset Matrix
F2: DQ Resistance

Failure Analysis

In process
In process, 960119